

Notice of References Cited

Application/Control No.

10/576,341

Applicant(s)/Patent Under
Reexamination
CHING, WEE SOON

Examiner

NANCY BITAR

Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,558,623	05-2003	Ganz et al.	422/63
*	B	US-6,902,702	06-2005	Winegarden et al.	422/100
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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